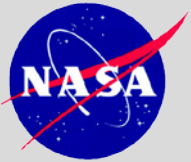


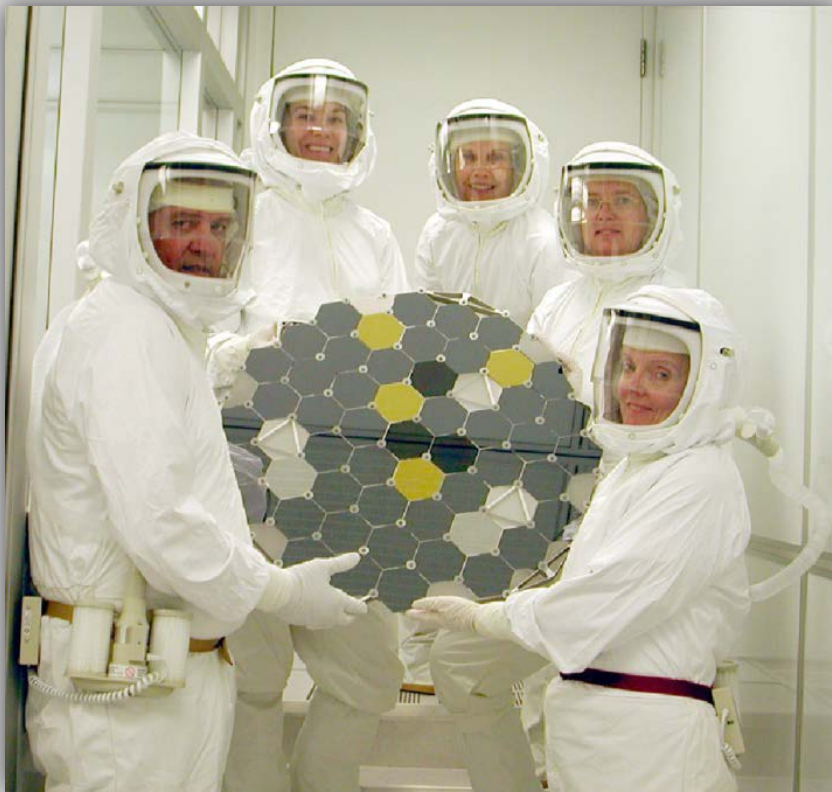
Overview Genesis Contamination Control and Curation

Judy Allton, Eileen Stansbery, Kim Cyr, Jack Warren, Carol
Schwarz, Jerome Hittle, Karen McNamara, Mike Calaway,
Melissa Rodriguez, P. J. Burkett, Vern Lauer, Carla Gonzalez,
Kimberly Allums



ASTROMATERIAL CURATION

JSC



- **Preservation of scientific integrity**
 - Controlled environment storage and handling
 - Controlled documentation and sample accountability
- **Characterizing the collection**
- **Dissemination of information about the collection**
- **Allocation of samples for research and education**
- **Reserve portion for future studies**

Responsibility assigned to Director of the Johnson Space Center per NASA Policy Directive 7100.10E

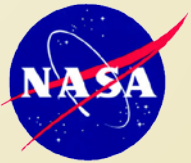


ASTROMATERIAL CURATION

JSC

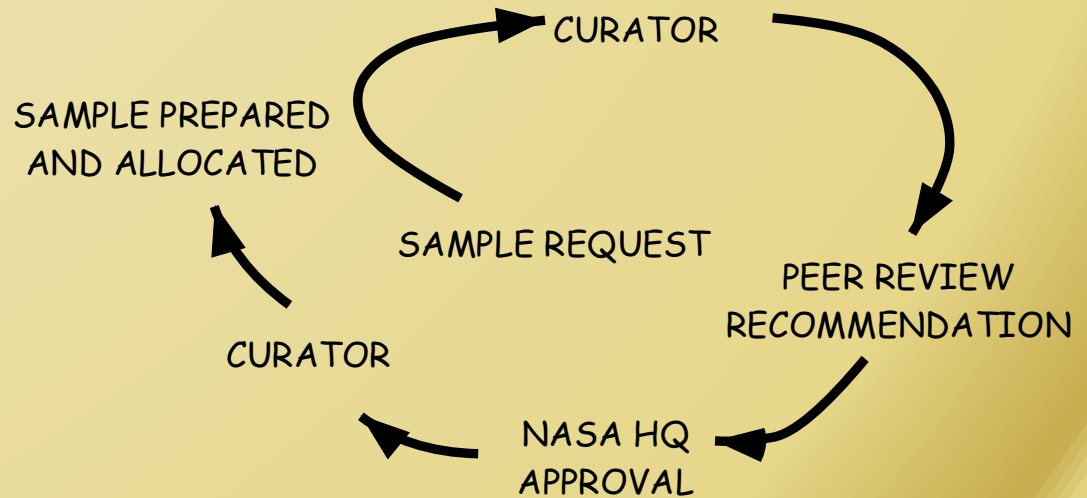
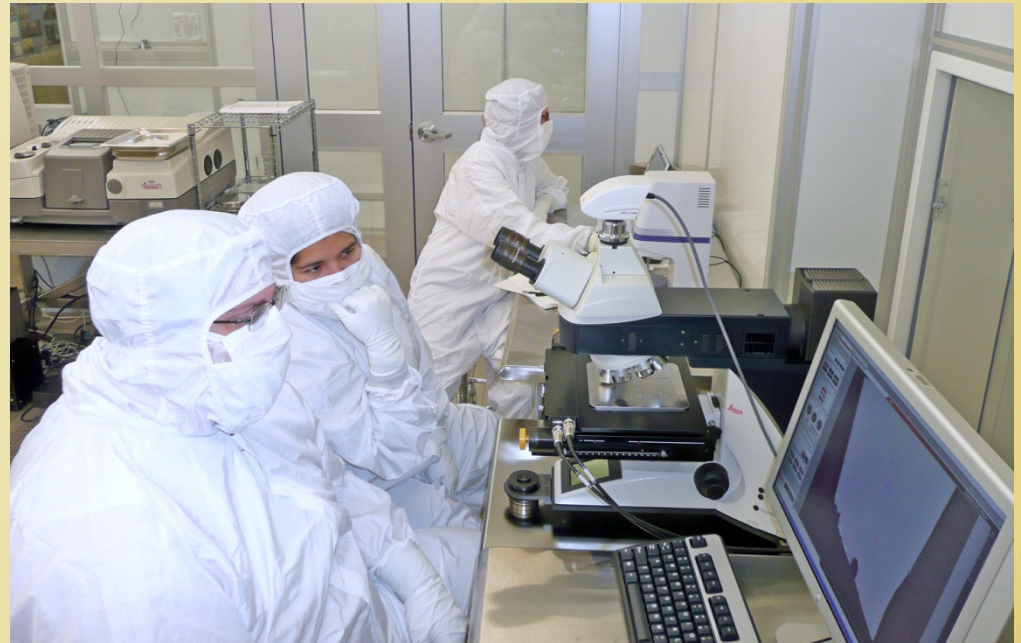


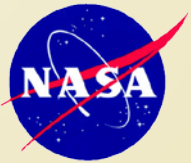
- **Begins with mission design and hardware design**
 - Set requirements for contamination control based on science requirements
 - Active participation in mission planning
- **Continues through fabrication, cleaning and assembly**
 - Attention to detail of fabrication and assembly process is critical
 - Active participation and contamination control oversight
- **Continues through launch, flight and return phases**
 - Active participation
- **Recovery operations optimized for scientific integrity**
- **Curatorial facility operation for preservation of scientific integrity**



CURATION – SCIENCE FROM THE SAMPLES

- Sample Characterization and documentation
- Dissemination of information about the collection
- Facilitating peer review and implementing allocation decisions



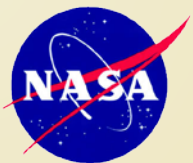


CURATION – SAMPLE ACCOUNTABILITY

JSC

- **Accurate tracking :**
collection inventories,
investigator
inventories



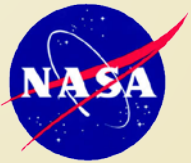


GENESIS DID IT RIGHT!

JSC



- **Mission plan and budget included contamination control and curation from the beginning**
- **Excellent team work among Principal Investigator, science team, mission design, engineering and curation**
- **“START CLEAN, STAY CLEAN”**
- **Post-landing intense collaboration between curation and science team on cleaning methods and cleanliness assessment**

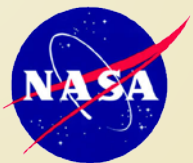


PRE-LAUNCH CURATION

JSC

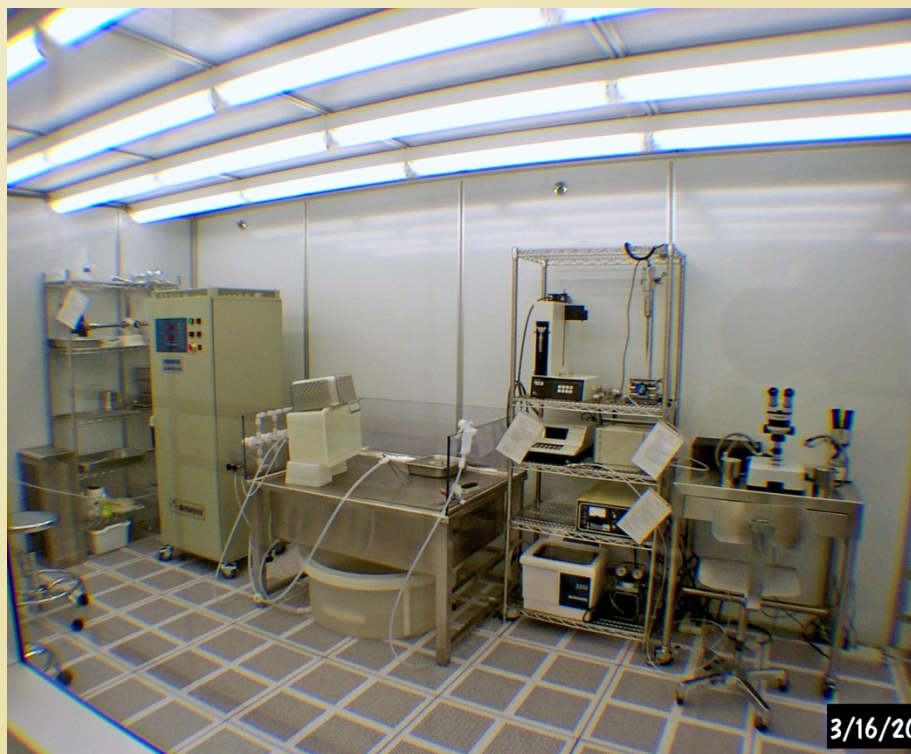


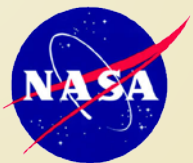
- **Assessment of contamination mitigation during flight operations**
 - Sealed payload open only during collection
 - Minimization of thruster plume effects
 - Re-entry pressure equalization and ablation gas mitigation
- **Choice of clean and cleanable materials for payload fabrication**
 - Bare aluminum, minimum lubricants and adhesives
- **Construction of ISO Class 4 cleanroom for payload cleaning & assembly**
 - Cleaning with megasonically energized ultrapure water: 18 meg-Ohm-cm
 - Assembly and sealing of payload
- **Archiving of flight reference coupons and environmental monitoring witness plates**
- **Clean sample storage under nitrogen**



PRE-LAUNCH CURATION: ISO 4 laminar flow cleanrooms

JSC

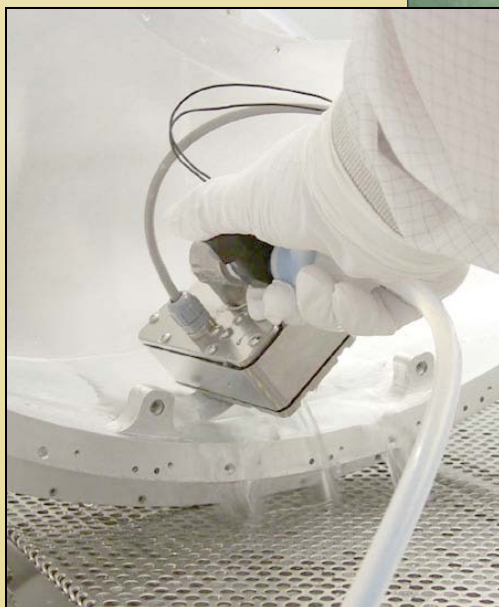


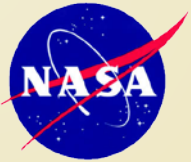


PRE-LAUNCH CURATION: Cleaning with UPW

JSC

- 18 M Ω -cm resistivity
- <5 ppb TOC
- Ultrasonic or megasonic energy
- Ionic concentration low parts per trillion = “hungry water”

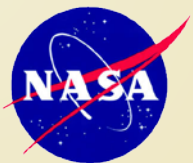




PRE-LAUNCH CURATION: Clean assembly, HEPA-filtered people

JSC





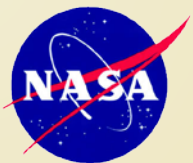
PRE-RECOVERY CURATION

JSC



- **Instrumentation for surface cleanliness assessment**
 - High resolution optical scanning for particulates
 - Ellipsometry mapping for molecular films

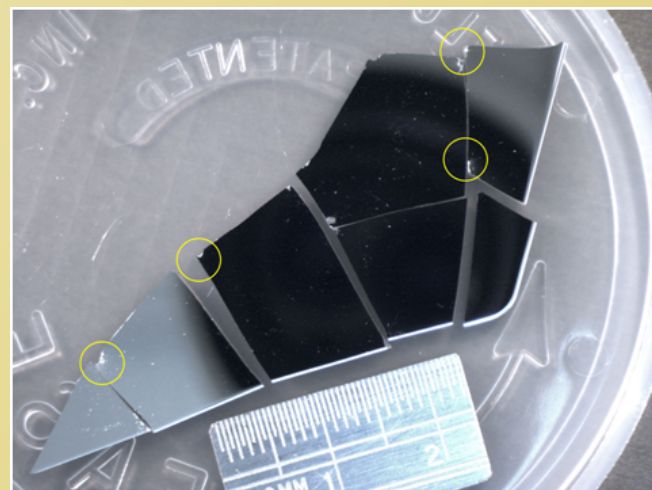
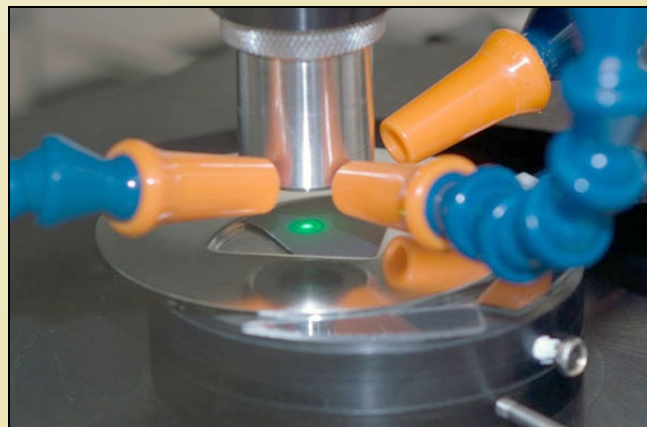


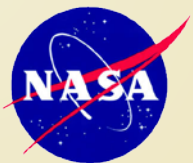


PRE-RECOVERY CURATION

JSC

- **Capability for clean subdivision of collectors**
 - Laser scribing backside
 - Manual cleaving



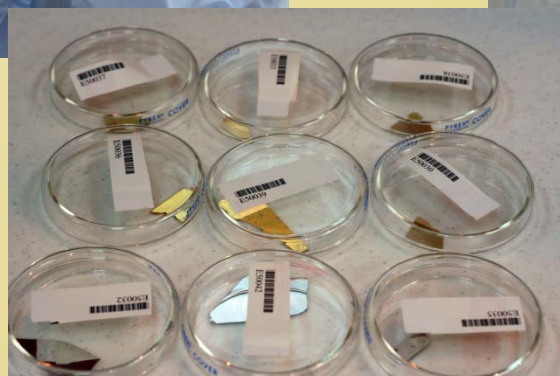


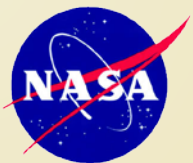
POST-LANDING CURATION

JSC

- **Landing site recovery**

- Field recovery to UTTR cleanroom before sunset
- Removal of collector fragments from canister
- Imaging and packaging of >10,000 fragments
- Transport to JSC in less than a month





JSC CURATION

JSC



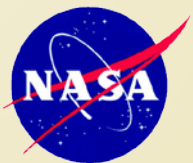
- Secure nitrogen storage
- ISO Class 4 handling
- Sample characterization
- Sample information dissemination
- Sample allocation



Oct. 7-9, 2014

GENESIS EARTH RETURN - 10th

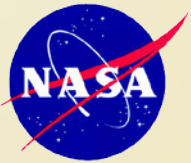
15



JSC CURATION: Secure nitrogen storage

JSC

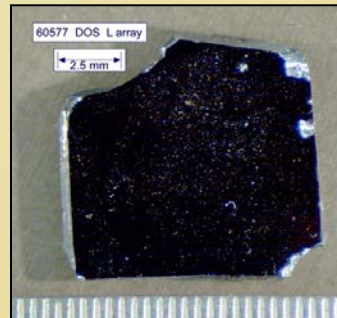
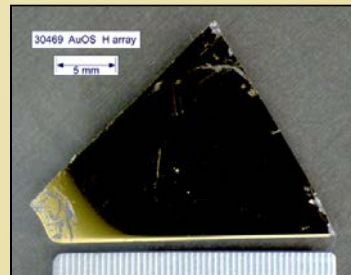
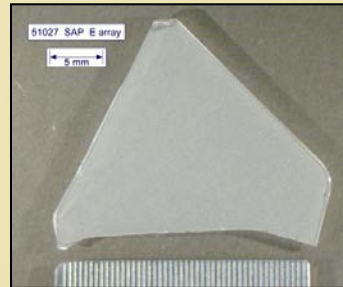




JSC CURATION: Sample characterization

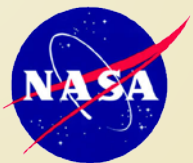
JSC

- Material
- Solar wind regime
- Imaging
- Size and surface quality



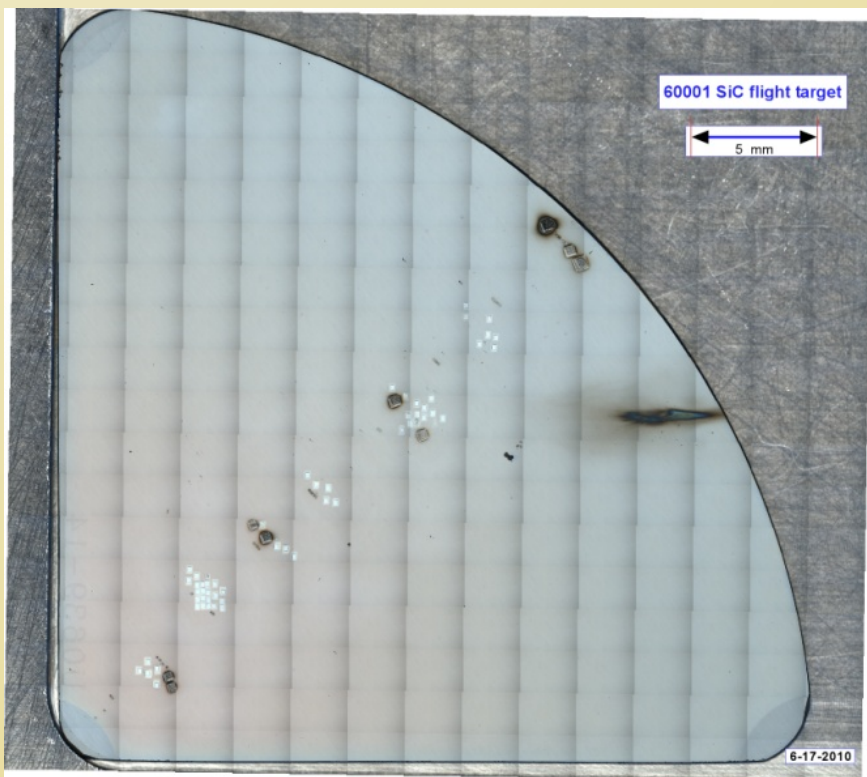
Oct. 7-9, 2014

GENESIS EARTH RETURN -

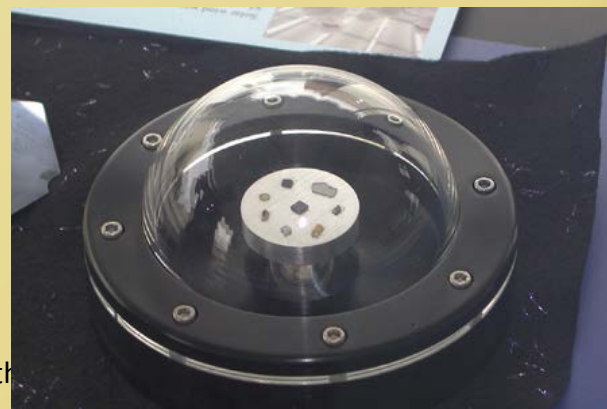


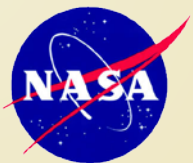
JSC CURATION: Dissemination of sample information, facilitation of peer review, allocation

JSC



- Online catalog updated monthly
- Newsletter
- Investigator Guidebook
- Genesis Oversight Subcommittee of CAPTEM reviews sample requests and recommendations to Discipline Scientist at NASA HQ
- Public display samples





JSC CURATION: Collaboration with science team, cleaning samples

JSC



- JSC optical imaging between cleaning steps
- JSC cleaning with ultrapure water (UPW)
- JSC use of UV ozone to remove molecular film



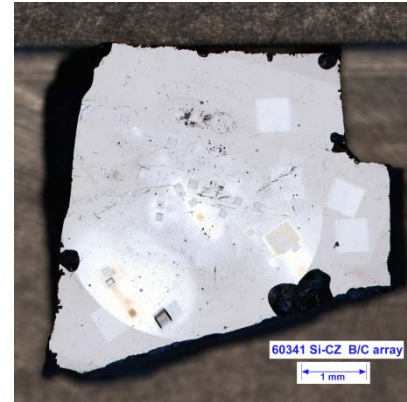
Sample History



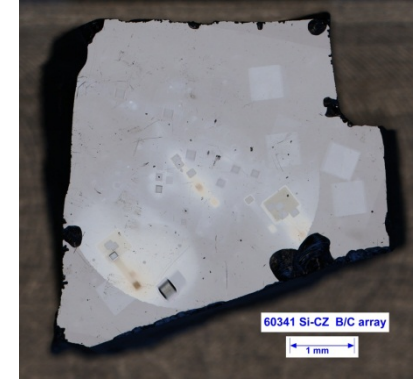
After UPW cleaning
(Step 1)



After UV ozone cleaning
(Step 4)



After ToF-SIMS analysis
(Step 5)



After UPW cleaning
(Step 8)

1. UPW cleaned (2/21/2007) *
2. 25Mg implant, SIMS analysis (6/12/2007)
3. 54Fe implant, SIMS analysis (5/1/2011)
4. UV ozone (6/22/2011) *
5. ToF-SIMS (3/11/2013) *
6. UPW cleaned (8/21/2013) *
7. HCl, hot xylene (8/28/2013) *
8. UPW cleaned (9/4/2013) *
9. ToF-SIMS (3/14/2014)

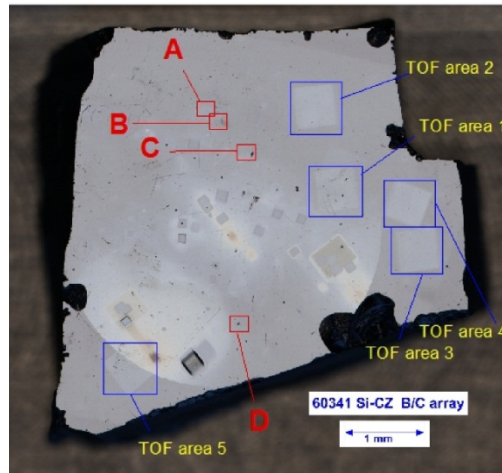
UPW= Ultra Pure Water

* Followed by optical imaging



Optical Images of 60341

JSC



Location of high magnification optical images and ToF-SIMS scans. Overall image taken after 3rd UPW cleaning-Step 8. The bright areas are oxidation introduced during SIMS analysis.

	After ToF-SIMS analysis (Step 5)	After UPW cleaning (Step 6)	After 6N HCl etching & hot xylene treatment (Step 7)	After UPW cleaning (Step 8)
Position A				
Position B				
Position C				
Position D				
ToF Area 1				

1. Step 6 shows UPW cleaning effectively removed handling debris documented in step 5 (ToF-SIMS);
2. Acid cleaning, hot xylene treatment, and ultrasonic cleaning (step 7) added contamination to positions A and B, but removed in C and D;
3. Images from step 8 show contamination from step 7 handling was partially mitigated in A and B, but there were few visible changes in C and D.



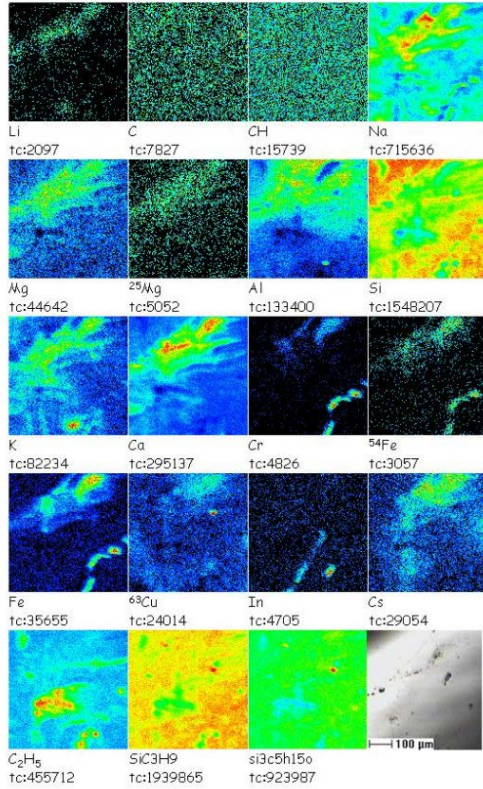
ToF-SIMS Results

JSC

60341 TOF area 1 before Ar sputtering

Positive ion imaging

Field of view: 500.0 x 500.0 μm^2

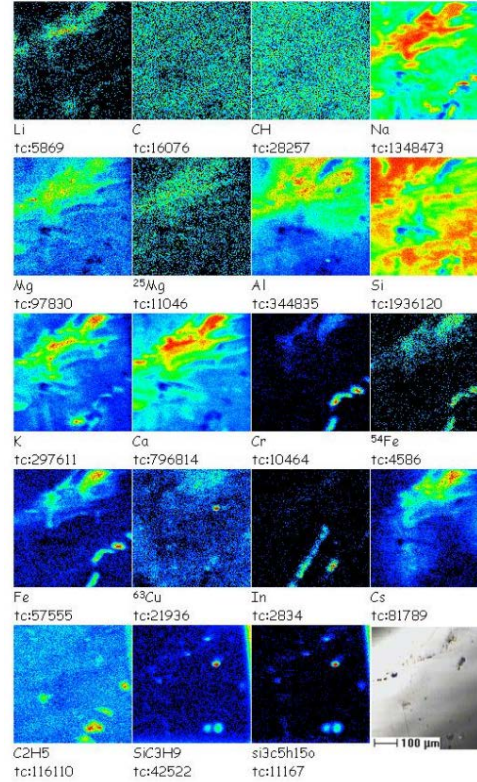


A) ToF-SIMS Area 1 after Step 4 Before Ar sputtering

60341 TOF area 1 after Ar sputtering

Positive ion imaging

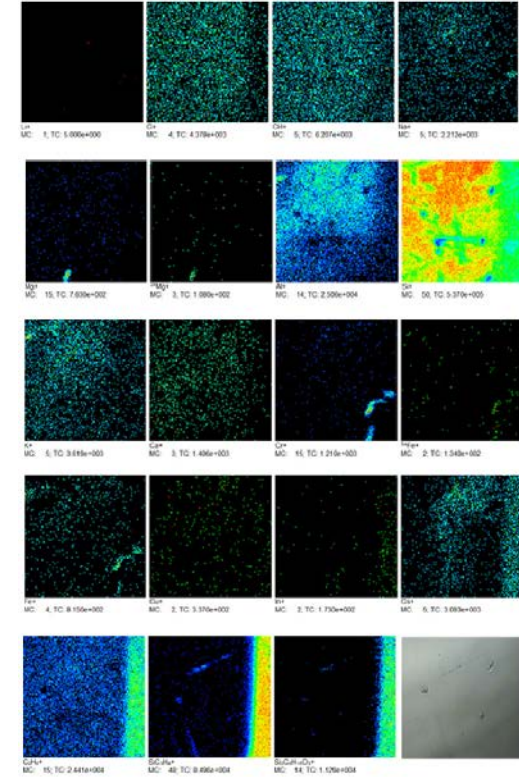
Field of view: 500.0 x 500.0 μm^2



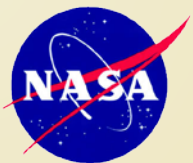
B) ToF-SIMS Area 1 after Step 4 After Ar sputtering

Positive ion imaging

Field of view: 500.0 x 500.0 μm^2



C) ToF-SIMS after Step 8 (last UPW)



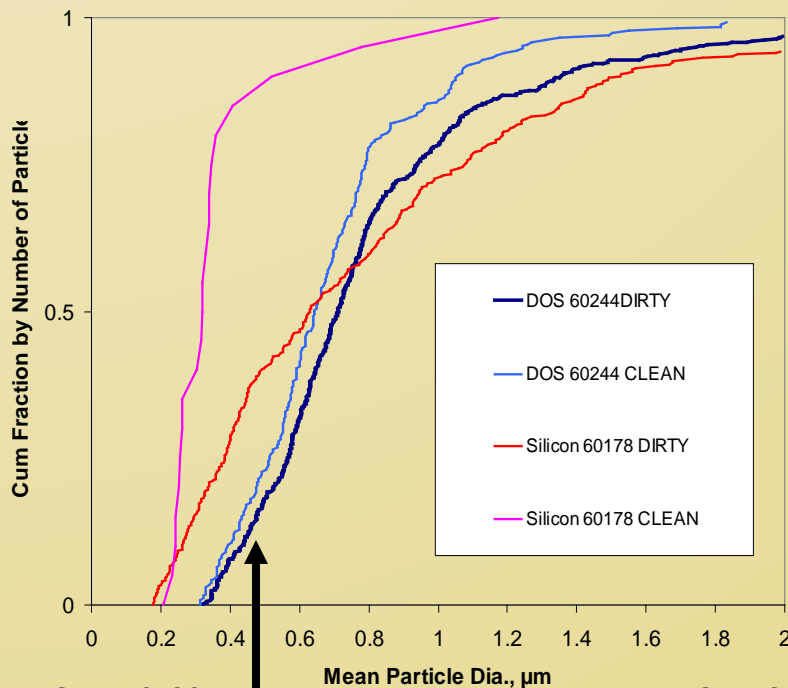
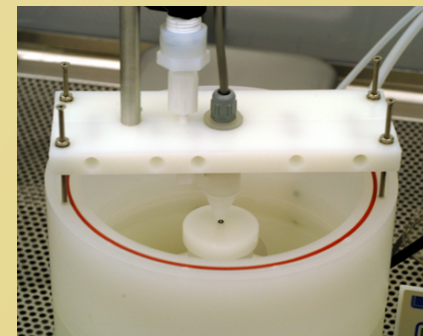
GENESIS SAMPLE CLEANING

JSC

- Brown stain removal - UV ozone cleaner



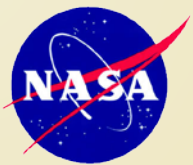
- Particle removal - UPW megasonic



0.5 μm

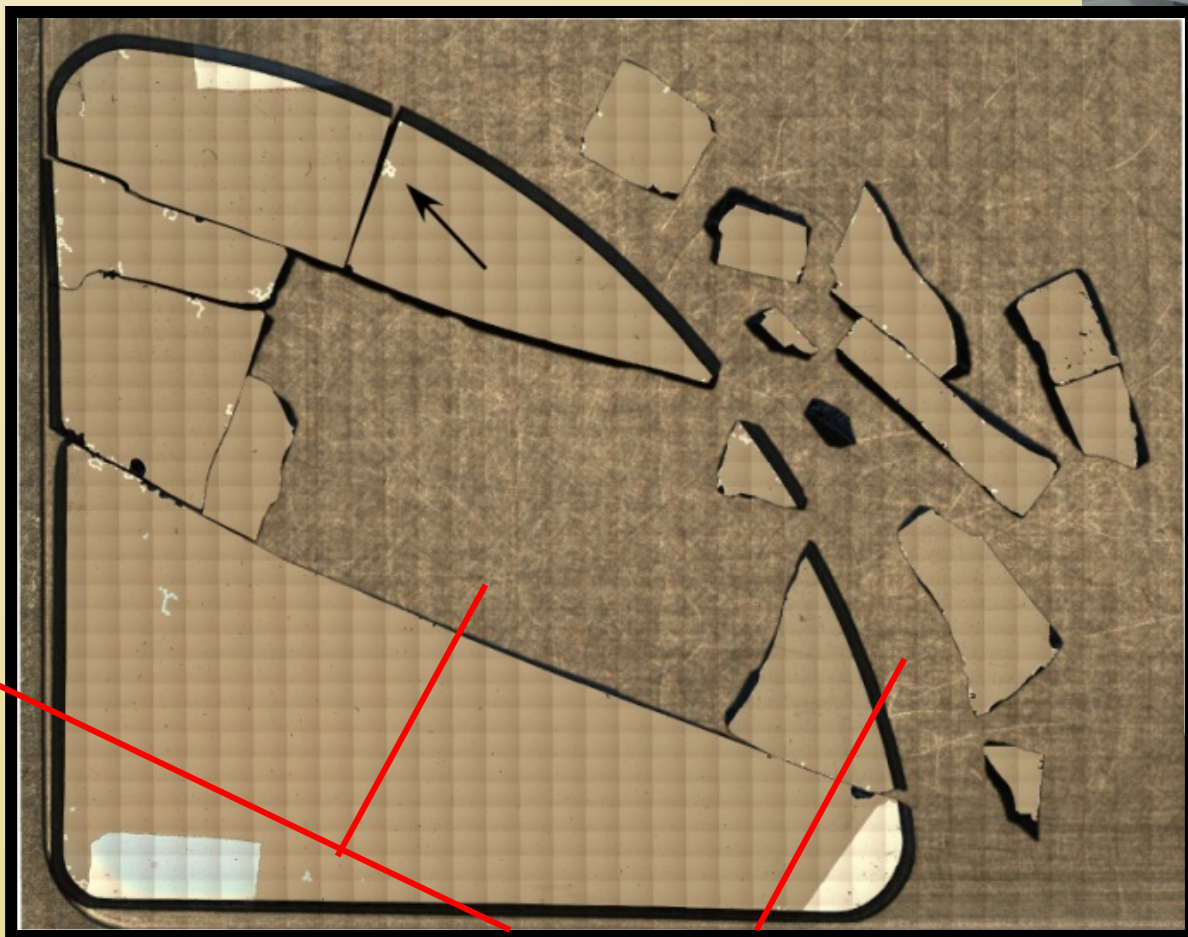
Oct. 7-9, 2014

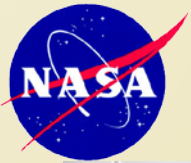
GENESIS EARTH RETURN - 10th



JSC CURATION: precise sample subdivision

JSC





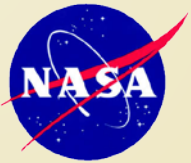
JSC CURATION: clean sample subdivision

JSC



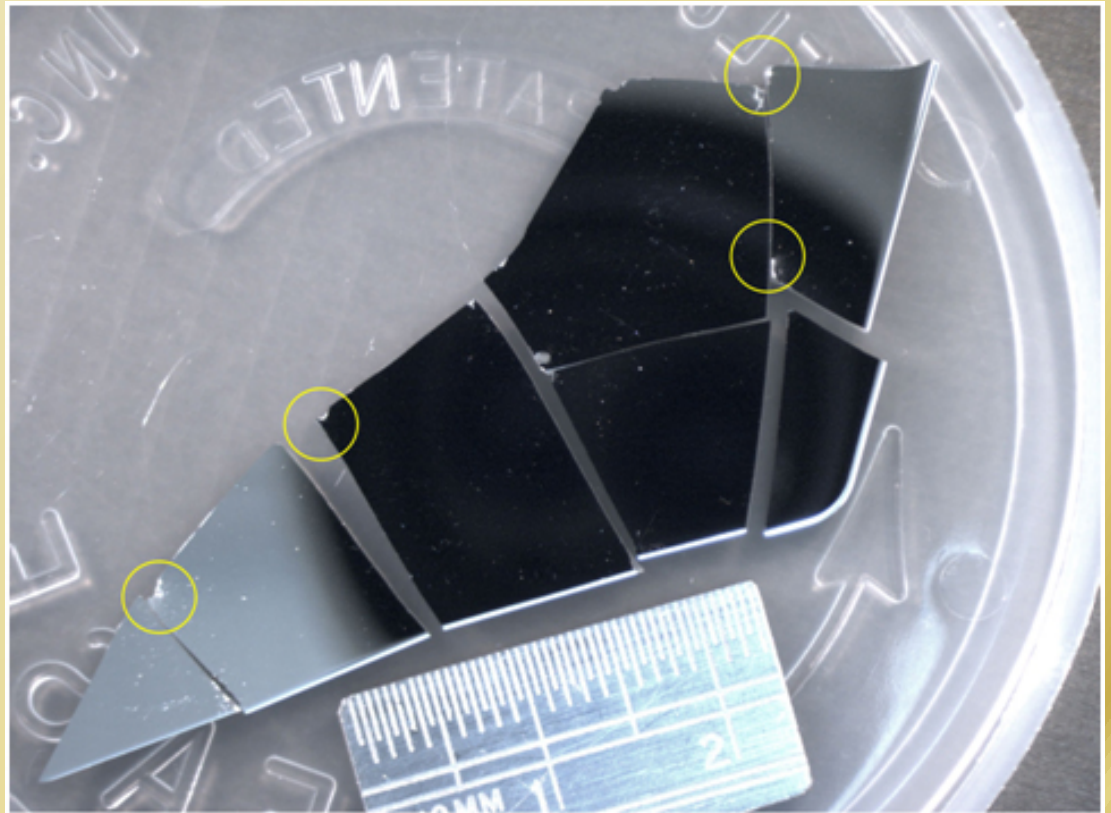
- Subdivision of polished aluminum –
- Yield material for noble gas analysis and two craters

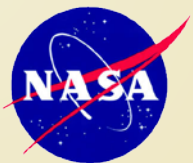




JSC CURATION: clean sample subdivision

JSC





JSC CURATION 10 YEARS: Samples characterized

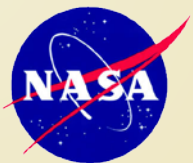
JSC

MATERIAL	ARRAY	FLOWN AREA (mm ²)	AREA CATALOGED (mm ²)	TOTAL CATALOGED (%)	
CZ Si	B	56493	3123.2	1.8	
	C	112986			
	H	43939	2219.0		5.1
	E	56493	2415.7		4.3
	L	56493	2426.7		4.3
FZ Si	B	125540	4580.7	2.0	
	C	100432			
	H	106709	1846.8		1.7
	E	106709	2412.8		2.3
	L	138094	1192.9		0.9
DOS	B	18831	1502.9	4.0	
	C	18831			
	H	25108	523.7		2.1
	E	25108	985.8		3.9
	L	25108	730.4		2.9

Data as of January 2009

MATERIAL	ARRAY	FLOWN AREA (mm ²)	AREA CATALOGED (mm ²)	TOTAL CATALOGED (%)	
SAP	B	25108	10976.0	21.9	
	C	25108			
	H	25108	12147.4		48.4
	E	31184	15096.6		48.4
	L	25108	2796.6		11.1
SOS	B	31385	33690.2	59.6	
	C	25108			
	H	25108	14878.5		59.3
	E	25108	16078.6		64.0
	L	25108	9542.6		38.0
AiOS	B	31184	30110.4	42.0	
	C	40499			
	H	31385	14747.8		47.0
	E	37461	16488.8		44.0
	L	25108	7992.7		31.8
AuOS	B	24907	31952.1	48.9	
	C	40499			
	H	62167	19060.8		30.7
	E	43738	29398.4		67.2
	L	43336	6744.4		15.6
CCo-AuOS	B	12353	6068.3	49.1	
	C	0	0.0	0.0	
	H	0	0.0	0.0	
	E	0	0.0	0.0	
	L	0	0.0	0.0	

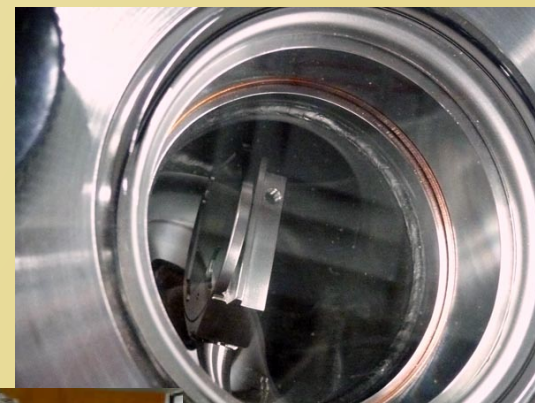
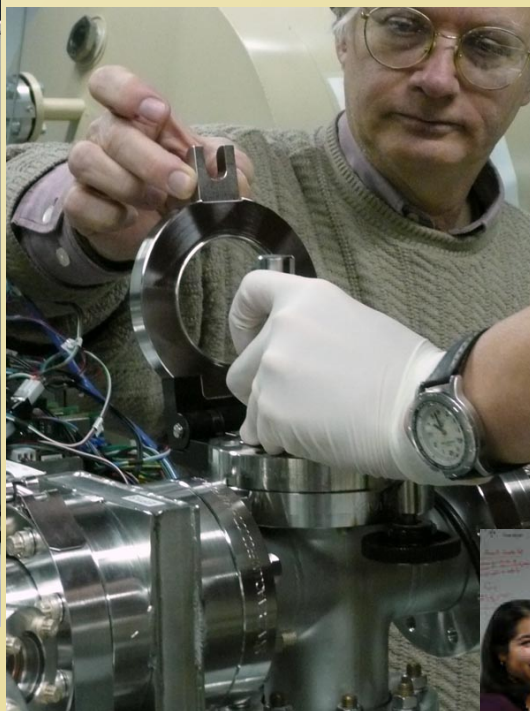
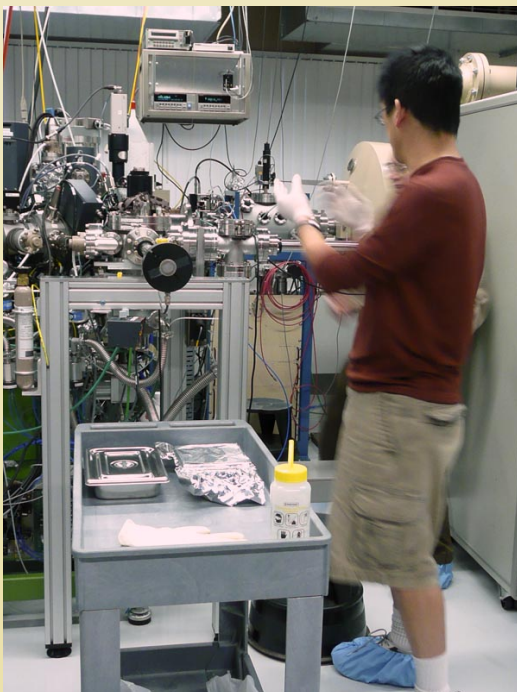
- Sapphire based: 15-49% cataloged
- Silicon based: 1-5% cataloged

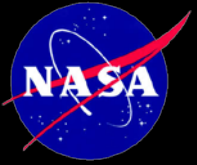


JSC CURATION 10 YEARS: Samples allocated

JSC

- 653 Genesis-flown samples
- 327 reference collectors
- 28 research groups in 6 countries





JSC